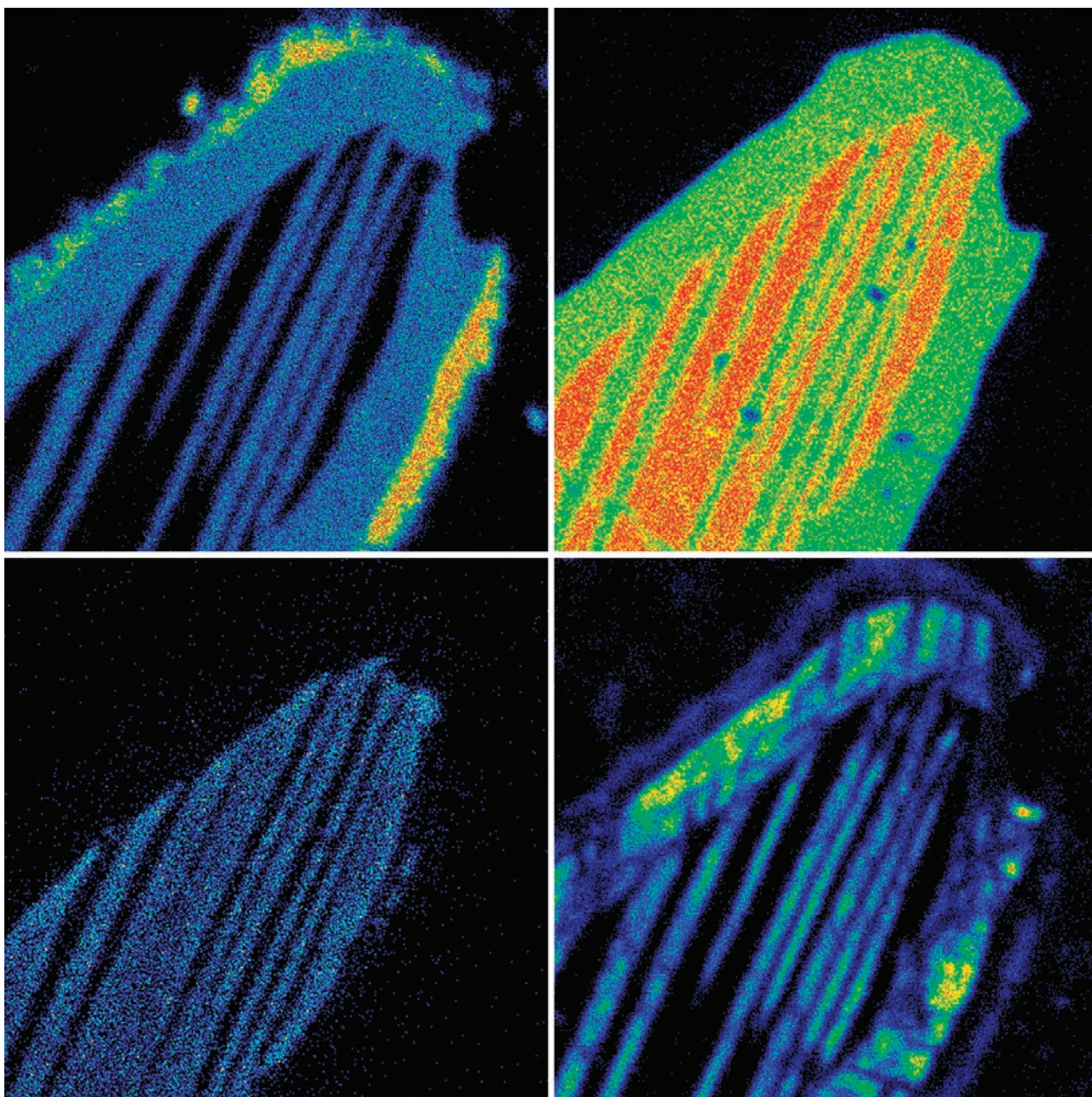


# Microscopy TODAY

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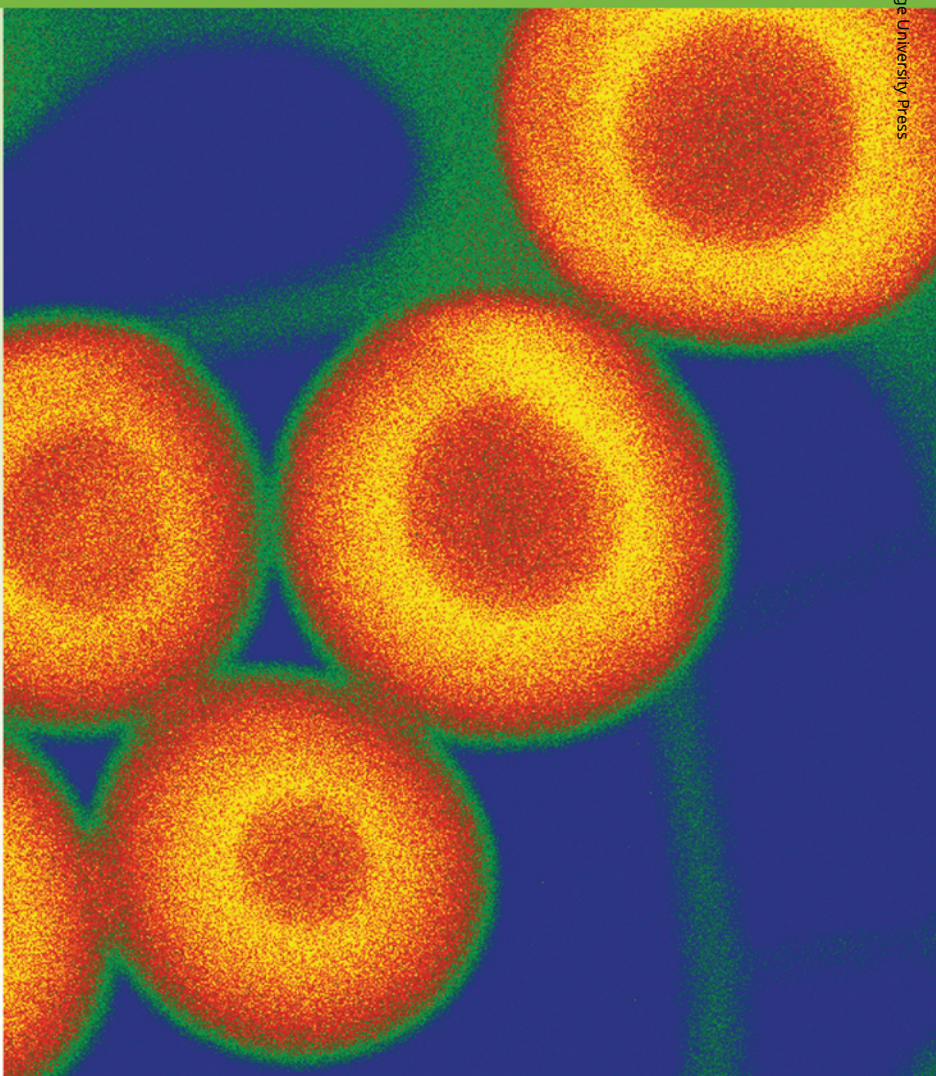
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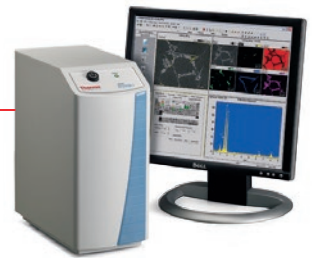
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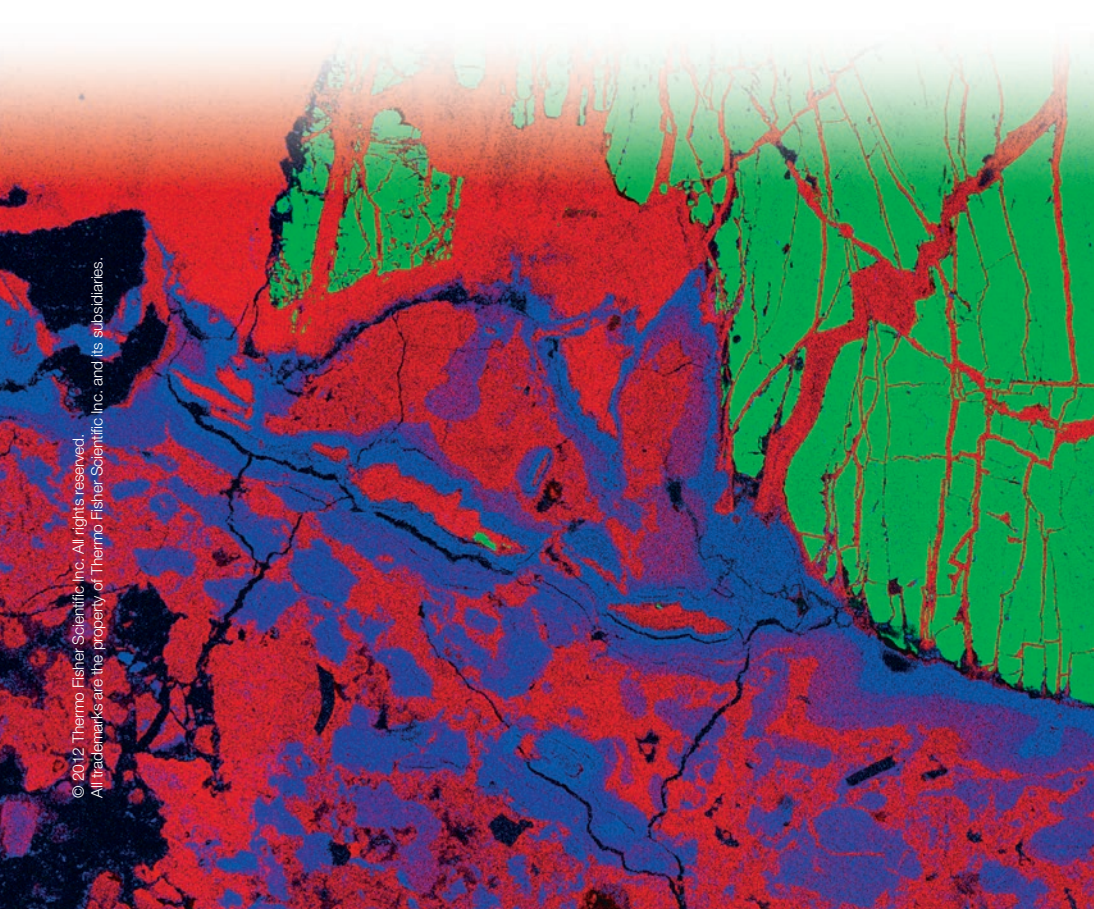
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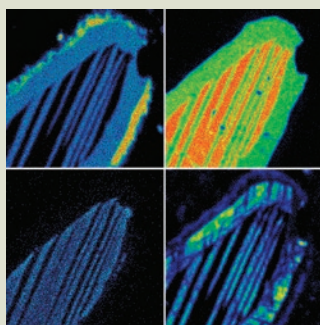
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### About the Cover



X-ray emission maps showing Fe, Ti, Nb, and Mg distributions in a flat-polished sample of hematite-ilmenite-rutile. Full width = 15  $\mu\text{m}$ .

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